

DETAILED ACTION

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it **MUST** be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with James Balls on May 22, 2008.

The application has been amended as follows:

Considering claim 8, after "the method of claim 3" please insert --wherein, the strain sensor consists of a polymer that has been irradiated with less than 1×10^{15} ions/cm² in a portion of its surface to exhibit strain dependent electrical properties for producing a measurable electrical signal that is linear with increasing strain and conducting tracks being deposited onto the treated portion to enable the sensor to be connected to an external electric circuit.--

Allowable Subject Matter

1. Claims 1-8 are allowed.
2. The following is an examiner's statement of reasons for allowance:
3. Considering claim 1, the prior art made of record fails to disclose, suggest or render obvious the use of a polymer irradiated with a fluence of less than 1×10^{15}

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ions/cm² so as to produce a strain sensor that exhibits stain dependent linear electrical signals with increasing strain and conducting tracks deposited onto the irradiated area to enable the sensor to be connected to an external electric circuit.

4. Considering claim 3, the prior art made of record fails to disclose, suggest or render obvious the method of producing a polymeric strain sensor having the steps of irradiating a surface with a fluence of less than 1×10^{15} ions/cm² so as to produce a strain sensor that exhibits stain dependent linear electrical signals with increasing strain.

5. Considering claim 8, the prior art made of record fails to disclose, suggest or render obvious the use of a polymer irradiated with a fluence of less than 1×10^{15} ions/cm² so as to produce a strain sensor that exhibits stain dependent linear electrical signals with increasing strain and conducting tracks deposited onto the irradiated area to enable the sensor to be connected to an external electric circuit made by irradiating a surface with a fluence of less than 1×10^{15} ions/cm² so as to produce a strain sensor that exhibits stain dependent linear electrical signals with increasing strain.

6. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Jonathan Dunlap whose telephone number is (571)270-1335. The examiner can normally be reached on M-F 9-5.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Edward Lefkowitz can be reached on (571) 272-2180. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/Edward Lefkowitz/

Supervisory Patent Examiner, Art Unit 2855

/J. D./
Examiner, Art Unit 2855
May 22, 2008